

# X RAY FLUORESCENCE SPECTROMETER/PLATING THICKNESS INSTRUMENT (ADVANCED TYPE) CODE XRF-PT230

MANUAL ZOOM



- Application fields: electroplating coating thickness analysis, inspection of electronic components such as connectors, fastener industry, automotive parts, hardware industry (household equipment and accessories, such as Cr/Ni/CuZn(ABS)), new energy industry (photovoltaic welding wire, etc.), thickness analysis of accessories, Ni/Cu/Ni/FendB on rubidium iron boron magnets, metal cation detection in electroplating solution, etc.
- It can detect 90 coating elements and analyze 77 elements in alloys.
- Equipped with a micro-focus X-ray generator and an advanced light path conversion focusing system, the minimum measurable area is up to 0.03mm<sup>2</sup>.
- It has non-destructive manual zoom detection technology, which can perform non-destructive testing on various shaped and irregular grooved parts from 0 to 30mm.
- Equipped with Si-Pin semiconductor detector, high resolution, fast testing speed, stable data, equipped with micro-light focusing technology, ranging spot diffusion less than 10%.
- The core EFP algorithm allows for the simultaneous analysis of 23 coating and 24 elements. It can quickly, accurately, and stably analyze multiple layers and multiple elements, including the same element in different layers.
- User-friendly closed software, automatically identifies faults, provides calibration and operation steps, and avoids misoperations.

## SPECIFICATION

Coating layer analysis	Elemental analysis range	Li(3)-U(92)
	Detection limit	0.005μm (detection limit for different elements is different)
	Analysis thickness	0.01-80μm (detection limit for different elements is different)
Composition analysis	Elemental analysis range	S(16)-U(92)
	Detection limit	2ppm (detection limit for different elements is different)
	Content analysis range	0.1%~99% (detection limit for different elements is different)
EFP algorithm	standard configuration	
Measuring time	5~300s	
Detector	Si-Pin semiconductor detector	
X-ray source	micro-focusing X-ray tube	
Collimator	standard: Φ0.3mm (Φ0.5mm, Φ0.3mm, Φ0.2mm, 0.1×0.3mm) four collimators optional, customized acceptable	
Nearest ranging spot diffusion	<10%	
Camera	1/2.7" color CCD, zoom function	
Measuring distance	zoom lens 0~30mm	
Focus method	high-sensitivity lens, manual focus	
Max. sample height	180mm	
XY stage	manual high-precision XY stage	
Available moving range	45mm×45mm	
Operating environment	15~30°C, <70%RH	
Power supply	AC220V, 50Hz, 95W	
Dimension (L×W×H)	545×380×435mm	
Weight	41kg	

**STANDARD DELIVERY**

<b>Main unit</b>	1 pc
<b>Computer</b>	1 pc
<b>Printer</b>	1 pc
<b>Accessory box</b>	1 pc
<b>Twelve element plate</b>	1 set
<b>Ni standard tablet</b>	1 pc
<b>Ag standard tablet</b>	1 pc

**OPTIONAL DELIVERY**

<b>Electroplating solution measuring cup</b>	<b>XRF-PT230-MC</b>
<b>Solution test membrane</b>	<b>XRF-PT230-SF</b>
<b>Au standard tablet</b>	<b>MSS-P01</b>
<b>Cr standard tablet</b>	<b>MSS-P02</b>
<b>Cu standard tablet</b>	<b>MSS-P03</b>
<b>Zn standard tablet</b>	<b>MSS-P04</b>